

Japan Traceability Committee Meeting Summary and Minutes

SEMICON Japan 2013
December 6, 2013, 3:00p.m. – 5:00 p.m.
International Conference Hall, Makuhari Messe, Chiba, Japan

Next Committee Meeting

April 25, 2014, 3:00 p.m. – 5:00 p.m. Japan Standard Time
Japan Standards Spring Meetings 2014, SEMI Japan, Office, Tokyo

Committee Announcements (optional)

None

Table 1 Meeting Attendees

Co-Chairs: Yoichi Iga (Renesas Electronics), Hirokazu Tsunobuchi (Keyence)

SEMI Staff: Hirofumi Kannno

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Keyence	Tsunobuchi	Hirokazu	Renesas Electronics	Iga	Yoichi
Fujitsu Semiconductor	Iida	Kiyokazu	Fujitsu Semiconductor	Hirasue	Terumi
NIST	Obeng	Yaw	AIST	Sakane	Hirofumi
Cosmos	Hamaguchi	Fusamitsu			

Table 2 Leadership Changes

None

Table 3 Authorized Ballots (or move to Section 7, New Business)

None

Table 4 Authorized Activities (or move to Section 7, New Business)

#	Type	SC/TF/WG	Details
TBA	SNARF	SiC Material and Wafer Specification TF	Line Item Revision of SEMI T5-1106 (Reapproved 1111) SPECIFICATION FOR ALPHANUMERIC MARKING OF ROUND COMPOUND SEMICONDUCTOR WAFERS

Note: SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 5 New Action Items (or move to Section 8, Action Item Review)

None

Table 6 Previous Meeting Actions Items (or move to Section 8, Action item Review)

None

1 Welcome, Reminders, and Introductions

Yoichi Iga called the meeting to order at 3:00 p.m. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Review of Previous Meeting Minutes

The committee reviewed the minutes of the previous meeting.

Motion: Approve the minutes of the previous meeting
By / 2nd: Hirokazu Tsunobuchi (Keyence) / Kiyokazu Iida (Fujitsu Semiconductor)
Discussion: None
Vote: 6:0

3 Liaison Reports

3.1 North America Traceability Committee

Hirofumi Kanno (SEMI) reported for the North America Traceability Committee. Of note:

- Committee Structure d& Leaders
- Meeting Information
- Ballot Results
- New SNARFs
- Upcoming Ballots
- Europe Compound Semiconductor Materials Committee Proposal

Attachment: 01, NA Traceability Liaison Report20131112

Motion: Approve the modified SNARF for *Line Item Revision of SEMI T5-1106 (Reapproved 1111) SPECIFICATION FOR ALPHANUMERIC MARKING OF ROUND COMPOUND SEMICONDUCTOR WAFERS*

By / 2nd: Hirokazu Tsunobuchi (Keyence) / Kiyokazu Iida (Fujitsu Semiconductor)
Discussion: The original SNARF contained a number of irrelevant comments which were deleted to create the modified SNARF.
Vote: 6:0

Attachment: 02, SNARF for LI Rev of T5

3.2 SEMI Staff Report

Hirofumi Kanno (SEMI) gave the SEMI Staff Report. Of note:

- Global SEMI Events
- Global Standards Meetings Schedule
- Ballot Critical Dates
- Publication Update
- SEMICON Japan 2013
- Contact Information

Attachment: 03, 4.0_SEMI Staff Report 2013 Dec._R0.1

4 Subcommittee & Task Force Reports

4.1 5 Year Review Task Force

Hirokazu Tsunobuchi (Keyence) reported that there was no activity for the Task Force.

4.2 Japan PV Traceability Task Force

Kiyokazu Iida (Fujitsu Semiconductor) reported for the Task Force. This report contained

Kiyokazu Iida, who was the originator of the Doc. 5594 *New Standard: Guide for Smart Label for PV Traceability*, gave up the document development.

4.3 Fiducial Mark Interoperability Task Force

Hirokazu Tsunobuchi (Keyence) briefly reported the activity.

Attachment: 04, 20131204FMI-TF-Report_r1

5 Old Business

None

6 New Business

6.1 Introduction for PUF: A Source of Unique IDs for Device Authentication and Traceability

Hirofumi Sakane (AIST) addressed the committee on this topic.

Attachment: 05, AIST 20131206

7 Action Item Review

7.1 *Open Action Items*

None

7.2 *New Action Items*

None

8 Next Meeting and Adjournment

April 25, 2014, 3:00 p.m. – 5:00 p.m. Japan Standard Time

Japan Standards Spring Meetings 2014, SEMI Japan, Office, Tokyo

Respectfully submitted by:
 Hirofumi Kanno
 Manager, Standards & EHS
 SEMI Japan
 Phone: +81.3222.5862
 Email: hkanno@semi.org

Minutes approved by:

Yoichi Iga (Renesas Electronics), Co-chair	<Date approved>
Hirokazu Tsunobuchi (Keyence), Co-chair	<Date approved>

Table 7 Index of Available Attachments #1

#	Title	#	Title
01	NA Traceability Liaison Report20131112	02	SNARF for LI Rev of T5
03	4.0_SEMI Staff Report 2013 Dec._R0.1	04	20131204FMI-TF-Report_r1
05	AIST 20131206		

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.